Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO220F "full pack" plastic package intended for use in applications requiring high bidirectional blocking voltage and high current surge capability with high thermal cycling performance.

2. Features and benefits

- · High bidirectional blocking voltage capability
- High current surge capability
- High thermal cycling performance
- Isolated mounting base package
- Planar passivated for voltage ruggedness and reliability

3. Applications

- · Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- Voltage regulation

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{RRM}	repetitive peak reverse voltage			-	-	650	V
I _{T(AV)}	average on-state current	half sine wave; T _h ≤ 69 °C		-	-	7.5	А
I _{T(RMS)}	RMS on-state current	half sine wave; T _h ≤ 69 °C; Fig. 1; Fig. 2; Fig. 3		-	-	12	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; T _{j(init)} = 25 °C; t _p = 10 ms; <u>Fig. 4</u> ; <u>Fig. 5</u>		-	-	120	А
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms		-	-	132	А
T _j	junction temperature			-	-	125	°C
Static ch	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C; } Fig. 7$		-	2	15	mA
Dynamic	Dynamic characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 436 V; T_j = 125 °C; R_{GK} = 100 Ω; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 12		200	1000	-	V/µs
		V_{DM} = 436 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12		50	130	-	V/µs

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	
2	А	anode		A K
3	G	gate		G sym037
mb	n.c.	mounting base; isolated		

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity		Package issue date
BT151X-650R	TO220F	BT151X-650R,127	Tube	50	SOT186A	14-Nov-2013

7. Marking

Table 4. Marking codes

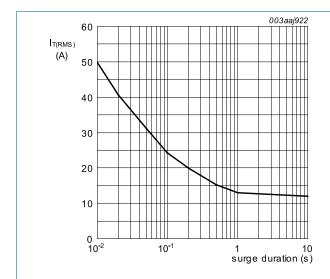
Type number	Marking codes		
	Assembly factory: d	Assembly factory: A	
BT151X-650R	BT151X 650R PJdxxxx xx	BT151X 650R PJAxxxx xx	

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	N	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-		650	V
V_{RRM}	repetitive peak reverse voltage		-		650	V
I _{T(AV)}	average on-state current	half sine wave; T _h ≤ 69 °C	-		7.5	А
I _{T(RMS)}	RMS on-state current	half sine wave; T _h ≤ 69 °C; Fig. 1; Fig. 2; Fig. 3	-		12	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 10 \text{ms}$; Fig. 4; Fig. 5	-		120	А
		half sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 8.3 \text{ms}$	-		132	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-		72	A²s
dl _⊤ /dt	rate of rise of on-state current	I _G = 30 mA	-		50	A/µs
I _{GM}	peak gate current		-		2	А
V_{RGM}	peak reverse gate voltage		-		5	V
P_{GM}	peak gate power		-		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-		0.5	W
T _{stg}	storage temperature		-	40	150	°C
T _j	junction temperature		-		125	°C



f = 50 Hz; T_h = 69 °C
Fig. 1. RMS on-state current as a function of surge duration; maximum values

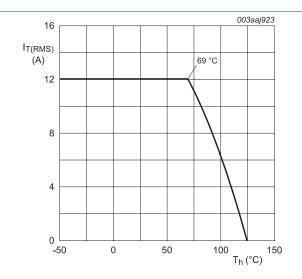
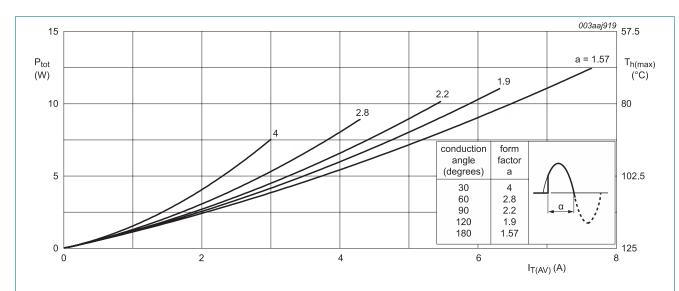


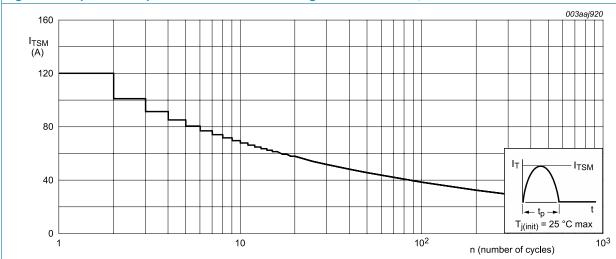
Fig. 2. RMS on-state current as a function of heatsink temperature; maximum values



 α = conduction angle

a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$

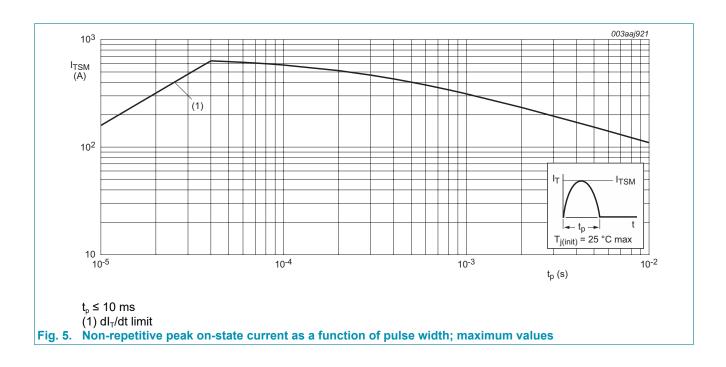
Fig. 3. Total power dissipation as a function of average on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

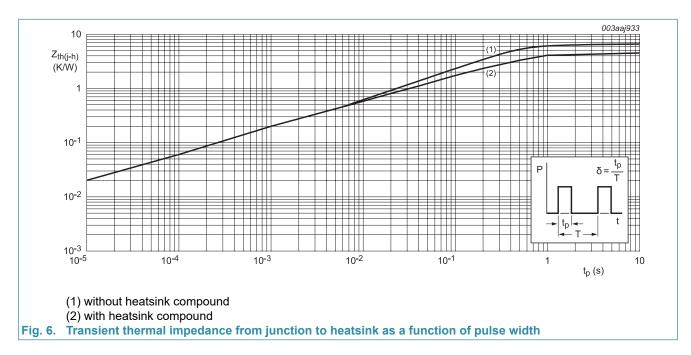
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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-h)}	thermal resistance	with heatsink compound; Fig. 6	-	-	4.5	K/W
	from junction to heatsink	without heatsink compound; Fig. 6	-	-	6.5	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W



10. Isolation characteristics

Table 7. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; $T_h = 25$ °C	-	-	2500	V
C _{isol}	isolation capacitance	from anode to external heatsink; f = 1 MHz; T_h = 25 °C	-	10	-	pF

11. Characteristics

Table 8. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	2	15	mA
I _L	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 8$	-	10	40	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	7	20	mA
V _T	on-state voltage	I _T = 23 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.4	1.75	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C;}$ Fig. 11	-	0.6	1	V
		$V_D = 650 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C}$	0.25	0.4	-	V
I _D	off-state current	V _D = 650 V; T _j = 125 °C	-	0.1	0.5	mA
I _R	reverse current	V _R = 650 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 436 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; Fig. 12	200	1000	-	V/µs
		V_{DM} = 436 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	50	130	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; V_D = 650 \text{ V}; I_G = 100 \text{ mA};$ $d_{IG}/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$	-	2	-	μs
t _q	commutated turn-off time	$V_{DM} = 436 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{TM} = 20 \text{ A};$ $V_R = 25 \text{ V}; (dI_T/dt)_M = 30 \text{ A/µs}; dV_D/$ $dt = 50 \text{ V/µs}; R_{GK(ext)} = 100 \Omega; (V_{DM} = 67\% \text{ of } V_{DRM})$	-	70	-	μs

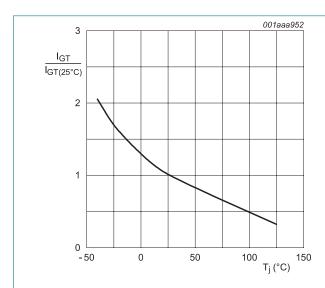


Fig. 7. Normalized gate trigger current as a function of junction temperature

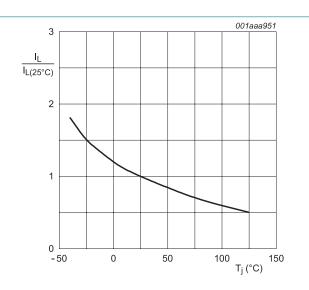


Fig. 8. Normalized latching current as a function of junction temperature

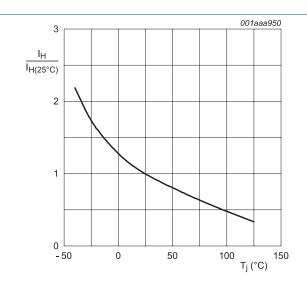
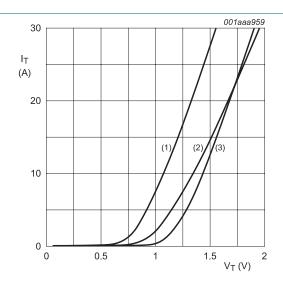


Fig. 9. Normalized holding current as a function of junction temperature



 V_o = 1.06 V; R_s = 0.0304 Ω (1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values

(3) $T_i = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

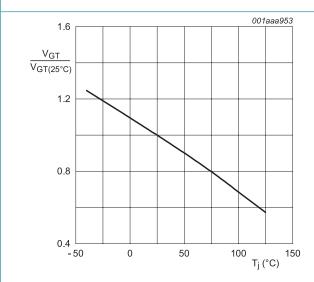
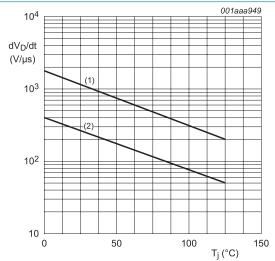


Fig. 11. Normalized gate trigger voltage as a function of junction temperature



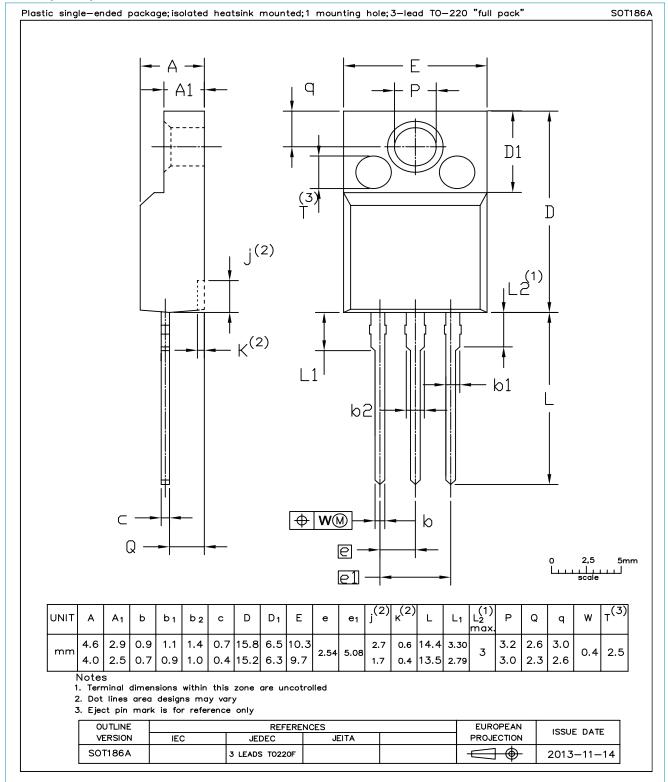
(1) $R_{GK} = 100 \Omega$;

(2) gate open circuit

Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; minimum

12. Package outline

Assembly factory: d & A



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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